TOSHIBA Power Transistor Module Silicon NPN Epitaxial Type (Four Darlington Power Transistors inOne)

MP4514

High Power Switching Applications
Hammer Drive, Pulse Motor Drive and Inductive Load
Switching

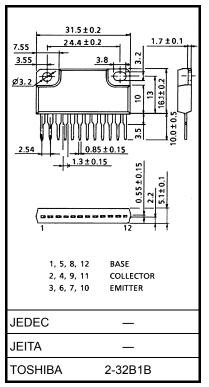
- Package with heat sink isolated to lead (SIP 12 pins)
- High collector power dissipation (4-device operation)
 P_T = 5 W (Ta = 25°C)
- High collector current: IC (DC) = 3 A (max)
- High DC current gain: $h_{FE} = 4000$ (min) ($V_{CE} = 4$ V, $I_{C} = 1$ A)

Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Collector-base voltage		V_{CBO}	120	V	
Collector-emitter voltage		V _{CEO}	100	V	
Emitter-base voltage		V _{EBO}	6	V	
Collector current	DC	IC	3	Α	
	Pulse	I _{CP}	4	A	
Continuous base current		I _B	0.5	Α	
Collector power dissipation (1-device operation)		PC	3.0	W	
Collector power dissipation	Ta = 25°C	Рт	5.0	W	
(4device operation)	Tc = 25°C	'	25	VV	
Isolation voltage		V _{Isol}	1000	V	
Junction temperature		Tj	150	°C	
Storage temperature range		T _{stg}	−55 to 150	°C	

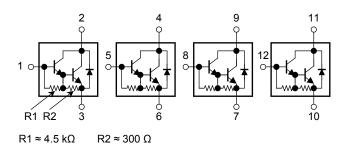
Industrial Applications

Unit: mm



Weight: 6.0 g (typ.)

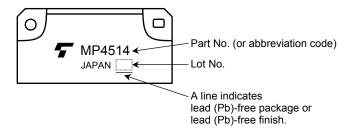
Array Configuration



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Marking



Thermal Characteristics

Characteristics	Symbol	Max	Unit	
Thermal resistance from channel to ambient	ΣR _{th (j-a)}	25	°C/W	
(4-device operation, Ta = 25°C)				
Thermal resistance from channel to case ΣR _{th (j}		5.0	°C/W	
(4-device operation, Tc = 25°C)	•			
Maximum lead temperature for soldering purposes	TL	260	°C	
(3.2 mm from case for 10 second)	_			

Electrical Characteristics (Ta = 25°C)

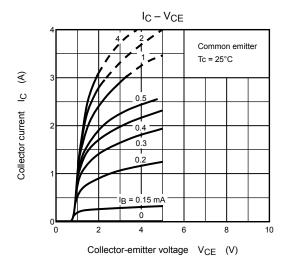
Charac	teristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Collector cut-off cu	rrent	I _{CBO}	V _{CB} = 120 V, I _E = 0 A	_	_	10	μA
Collector cut-off cu	rrent	I _{CEO}	V _{CE} = 100 V, I _B = 0 A	_	_	10	μA
Emitter cut-off curre	ent	I _{EBO}	V _{EB} = 6 V, I _C = 0 A	0.5	_	2.5	mA
Collector-base brea	akdown voltage	V (BR) CBO	I _C = 1 mA, I _E = 0 A	120	_	_	V
Collector-emitter bi	reakdown voltage	V (BR) CEO	I _C = 10 mA, I _B = 0 A	100	_	_	V
DC current gain		h _{FE (1)}	V _{CE} = 4 V, I _C = 1 A	4000	_	15000	
		h _{FE (2)}	V _{CE} = 4 V, I _C = 2 A	1000	_	_	_
Saturation voltage	Collector-emitter	V _{CE} (sat)	I _C = 1 A, I _B = 1 mA	_	_	1.5	V
	Base-emitter	V _{BE} (sat)	I _C = 1 A, I _B = 1 mA	_	_	2.0	
Transition frequence	cy	f _T	V _{CE} = 2 V, I _C = 0.5 A	_	100	_	MHz
Collector output capacitance		C _{ob}	V _{CB} = 10 V, I _E = 0 A, f = 1 MHz	_	20	_	pF
Switching time Storage time Fall time	Turn-on time	t _{on}	Output Input B1 CC S VCC = 30 V	_	0.4	_	
	Storage time	t _{stg}		_	4.0	_	μs
	Fall time	t _f	$I_{B1} = -I_{B2} = 1 \text{ mA, duty cycle} \le 1\%$	_	0.6	_	

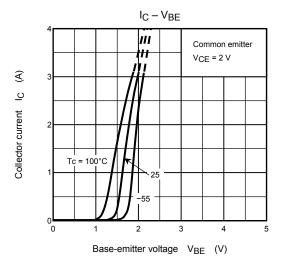
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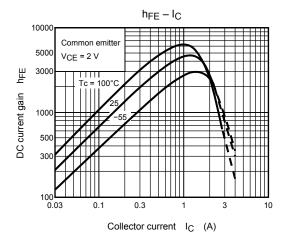
Emitter-Collector Diode Ratings and Characteristics (Ta = 25°C)

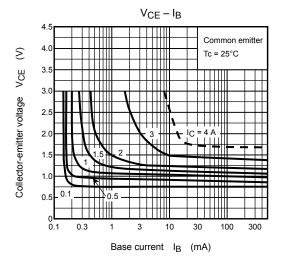
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Forward current	I _{FM}	_	_	_	2	Α
Surge current	I _{FSM}	t = 1 s, 1 shot	_	_	4	Α
Forward voltage	V _F	I _F = 0.5 A, I _B = 0 A	_	_	2.0	V
Reverse recovery time	t _{rr}	- I _F = 2 A, V _{BE} = -3 V, dI _F /dt = -50 A/μs	_	1.0	_	μs
Reverse recovery charge	Q _{rr}		_	5	_	μC

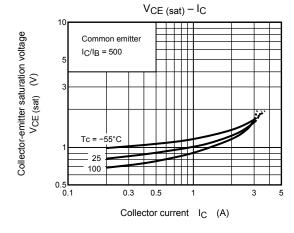
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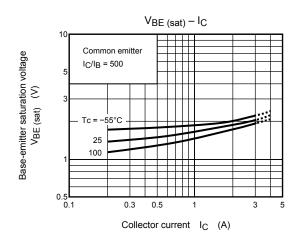


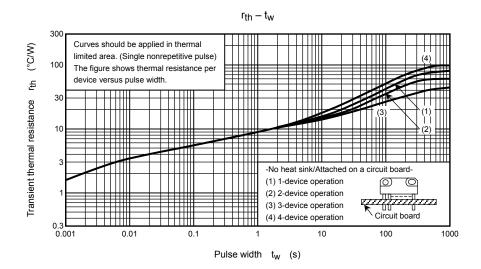


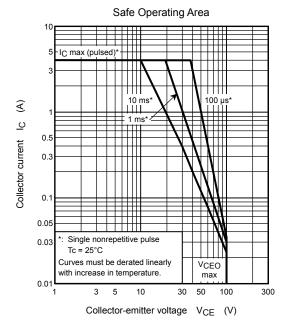


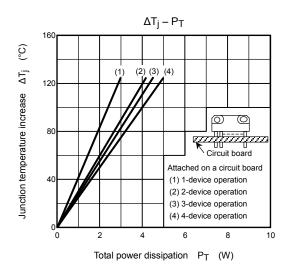


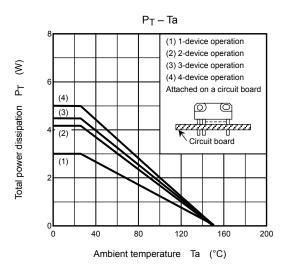












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